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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: Unassigned  
Examiner: Unassigned

In Re PATENT APPLICATION OF:

Applicant(s)	:	Kazutaka SHIBATA	)	
			)	
Serial No.	:	Divisional of Appl. Serial No. 10/088,163	)	
			)	
Filed	:	March 10, 2004	)	<b>INFORMATION</b>
			)	<b><u>DISCLOSURE</u></b>
For	:	SEMICONDUCTOR DEVICE AND METHOD	)	
		FOR MANUFACTURING THE SAME	)	
			)	
Attorney Ref.	:	KAW 110 D1	)	_____

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, attached are copies of the Forms PTO-1449 from the parent application, serial number, **10/088,163**, which the Examiner may wish to consult during examination of this Divisional Application thereof.

Respectfully submitted,



Steven M. Rabin (Reg. No. 29.102)  
RABIN & BERDO, PC  
Customer No. 23995  
Telephone: 202-371-8976  
Facsimile: 202-408-0924

March 10, 2004  
Date

SMR:tl

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**No. 18-0002**



DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

KWM-001

SERIAL NO.

10/088,163

APPLICANT

SHIBATA

FILING DATE

5/15/02

GROUP

2811

## REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

JUN 07 2002

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
AG	2-159047	06/90	JAPAN					X
AH	9-8046	01/97	JAPAN					X
AI	9-213702	08/97	JAPAN					X
AJ	9-326465	12/97	JAPAN					X
AK	2000-243785	09/00	JAPAN					X
AL								

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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AN	
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EXAMINER

DATE CONSIDERED

\*EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.